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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "<u>Embedded - Microcontrollers</u>"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	48MHz
Connectivity	CANbus, EBI/EMI, I <sup>2</sup> C, MMC/SD, QSPI, SCI, SPI, SSI, UART/USART, USB
Peripherals	DMA, LCD, LVD, POR, PWM, WDT
Number of I/O	104
Program Memory Size	512KB (512K x 8)
Program Memory Type	FLASH
EEPROM Size	8K x 8
RAM Size	96K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 5.5V
Data Converters	A/D 26x14b; D/A 3x8b, 3x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	121-LFBGA
Supplier Device Package	121-LFBGA (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r7fs3a37a2a01cbj-ac0

Table 1.7 Timers

Feature	Functional description
General PWM Timer (GPT)	The General PWM Timer (GPT) is a 32-bit timer with 4 channels and a 16-bit timer with 6 channels. PWM waveforms can be generated by controlling the up-counter, down-counter, or the up- and down-counter. In addition, PWM waveforms can be generated for controlling brushless DC motors. The GPT can also be used as a general-purpose timer. See section 23, General PWM Timer (GPT) in User's Manual.
Port Output Enable for GPT (POEG)	Use the Port Output Enable for GPT (POEG) function to place the General PWM Timer (GPT) output pins in the output disable state. See section 22, Port Output Enable for GPT (POEG) in User's Manual.
Asynchronous General Purpose Timer (AGT)	The Asynchronous General Purpose Timer (AGT) is a 16-bit timer that can be used for pulse output, external pulse width or period measurement, and counting of external events. This 16-bit timer consists of a reload register and a down-counter. The reload register and the down-counter are allocated to the same address, and they can be accessed with the AGT register. See section 24, Asynchronous General Purpose Timer (AGT) in User's Manual.
RealTime Clock (RTC)	The RealTime Clock (RTC) has two counting modes, calendar count mode and binary count mode, that are controlled by the register settings.  For calendar count mode, the RTC has a 100-year calendar from 2000 to 2099 and automatically adjusts dates for leap years.  For binary count mode, the RTC counts seconds and retains the information as a serial value. Binary count mode can be used for calendars other than the Gregorian (Western) calendar. See section 25, RealTime Clock (RTC) in User's Manual.

Table 1.8 Communication interfaces (1 of 2)

Feature	Functional description
Serial Communications Interface (SCI)	The Serial Communication Interface (SCI) is configurable to five asynchronous and synchronous serial interfaces:  • Asynchronous interfaces (UART and asynchronous communications interface adapter (ACIA))  • 8-bit clock synchronous interface  • Simple IIC (master-only)  • Simple SPI  • Smart card interface.  The smart card interface complies with the ISO/IEC 7816-3 standard for electronic signals and transmission protocol.  SCI0 and SCI1 have FIFO buffers to enable continuous and full-duplex communication, and the data transfer speed can be configured independently using an on-chip baud rate generator. See section 29, Serial Communications Interface (SCI) in User's Manual.
I <sup>2</sup> C bus interface (IIC)	The 3-channel I2C bus interface (IIC) conforms with and provides a subset of the NXP I2C (Inter-Integrated Circuit) bus interface functions. See section 30, I2C Bus Interface (IIC) in User's Manual.
Serial Peripheral Interface (SPI)	Two independent Serial Peripheral Interface (SPI) channels are capable of high-speed, full-duplex synchronous serial communications with multiple processors and peripheral devices. See section 32, Serial Peripheral Interface (SPI) in User's Manual.
Serial Sound Interface Enhanced (SSIE)	The Serial Sound Interface Enhanced (SSIE) peripheral provides functionality to interface digital audio devices for transmitting PCM audio data over a serial bus with the MCU. The SSIE supports an audio clock frequency of up to 25 MHz, and can be operated as a slave or master receiver/transmitter/transceiver to suit various applications. The SSIE includes 8-stage FIFO buffers in the receiver and transmitter, and supports interrupts and DMA-driven data reception and transmission. See section 35, Serial Sound Interface Enhanced (SSIE) in User's Manual.
Quad Serial Peripheral Interface (QSPI)	The Quad Serial Peripheral Interface (QSPI) is a memory controller for connecting a serial ROM (nonvolatile memory such as a serial flash memory, serial EEPROM, or serial FeRAM) that has an SPI-compatible interface. See section 33, Quad Serial Peripheral Interface (QSPI) in User's Manual.

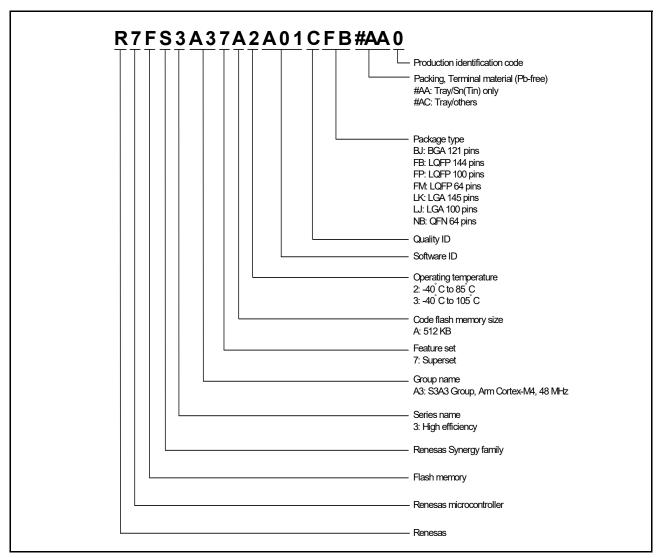


Figure 1.2 Part numbering scheme

Table 1.13 Product list

Product part number	Orderable part number	Package code	Code flash	Data flash	SRAM	Operating temperature
R7FS3A37A2A01CLK	R7FS3A37A2A01CLK#AC0	PTLG0145KA-A	512 KB	8 KB	96 KB	-40 to +85°C
R7FS3A37A3A01CFB	R7FS3A37A3A01CFB#AA0	PLQP0144KA-B				-40 to +105°C
R7FS3A37A2A01CBJ	R7FS3A37A2A01CBJ#AC0	PLBG0121JA-A				-40 to +85°C
R7FS3A37A3A01CFP	R7FS3A37A3A01CFP#AA0	PLQP0100KB-B				-40 to +105°C
R7FS3A37A2A01CLJ	R7FS3A37A2A01CLJ#AC0	PTLG0100JA-A				-40 to +85°C
R7FS3A37A3A01CFM	R7FS3A37A3A01CFM#AA0	PLQP0064KB-C				-40 to +105°C
R7FS3A37A3A01CNB	R7FS3A37A3A01CNB#AC0	PWQN0064LA-A				-40 to +105°C

# 1.5 Pin Functions

Function	Signal	I/O	Description
Power supply	VCC	Input	Power supply pin. Connect it to the system power supply. Connect this pin to VSS by a 0.1-µF capacitor. The capacitor should be placed close to the pin.
	VCL	Input	Connect this pin to the VSS pin by the smoothing capacitor used to stabilize the internal power supply. Place the capacitor close to the pin.
	VSS	Input	Ground pin. Connect it to the system power supply (0 V).
	VBATT	Input	Backup power pin
Clock	XTAL	Output	Pins for a crystal resonator. An external clock signal can be input through
	EXTAL	Input	the EXTAL pin.
	XCIN	Input	Input/output pins for the sub-clock oscillator. Connect a crystal resonator
	XCOUT	Output	between XCOUT and XCIN.
	EBCLK	Output	Outputs the external bus clock for external devices
	CLKOUT	Output	Clock output pin
Operating mode control	MD	Input	Pins for setting the operating mode. The signal levels on these pins must not be changed during operation mode transition at the time of release from the reset state.
System control	RES	Input	Reset signal input pin. The MCU enters the reset state when this signal goes low.
CAC	CACREF	Input	Measurement reference clock input pin
Interrupt	NMI	Input	Non-maskable interrupt request pin
	IRQ0 to IRQ15	Input	Maskable interrupt request pins
KINT	KR00 to KR07	Input	A key interrupt can be generated by inputting a falling edge to the key interrupt input pins
On-chip debug	TMS	I/O	On-chip emulator or boundary scan pins
	TDI	Input	
	TCK	Input	
	TDO	Output	
	SWDIO	I/O	Serial Wire debug Data Input/Output pin
	SWCLK	Input	Serial Wire Clock pin
	SWO	Output	Serial Wire trace Output pin
External bus interface	RD	Output	Strobe signal which indicates that reading from the external bus interface space is in progress, active-low
	WR	Output	Strobe signal which indicates that writing to the external bus interface space is in progress, in 1-write strobe mode, active-low
	WR0, WR1	Output	Strobe signals which indicate that either group of data bus pins (D07 to D00, D15 to D08) is valid in writing to the external bus interface space, in byte strobe mode, active-low
	BC0, BC1	Output	Strobe signals which indicate that either group of data bus pins (D07 to D00, D15 to D08) is valid in access to the external bus interface space, in 1-write strobe mode, active-low
	ALE	Output	Address latch signal when address/data multiplexed bus is selected
	WAIT	Input	Input pin for wait request signals in access to the external space, active-low
	CS0 to CS3	Output	Select signals for CS areas, active-low
	A00 to A23	Output	Address bus
	D00 to D15	I/O	Data bus
Battery backup	VBATWIO0 to VBATWIO2	I/O	Output wakeup signal for the VBATT wakeup control function.  External event input for the VBATT wakeup control function.

Function	Signal	I/O	Description					
GPT	GTETRGA, GTETRGB	Input	External trigger input pin					
	GTIOC0A to GTIOC9A, GTIOC0B to GTIOC9B	I/O	Input capture, Output capture, or PWM output pin					
	GTIU	Input	Hall sensor input pin U					
	GTIV	Input	Hall sensor input pin V					
	GTIW	Input	Hall sensor input pin W					
	GTOUUP	Output	3-phase PWM output for BLDC motor control (positive U phase)					
	GTOULO	Output	3-phase PWM output for BLDC motor control (negative U phase)					
	GTOVUP	Output	3-phase PWM output for BLDC motor control (positive V phase)					
	GTOVLO	Output	3-phase PWM output for BLDC motor control (negative V phase)					
	GTOWUP	Output	3-phase PWM output for BLDC motor control (positive W phase)					
	GTOWLO	Output	3-phase PWM output for BLDC motor control (negative W phase)					
AGT	AGTEE0, AGTEE1	Input	External event input enable					
	AGTIO0, AGTIO1	I/O	External event input and pulse output					
	AGTO0, AGTO1	Output	Pulse output					
	AGTOA0, AGTOA1	Output	Output compare match A output					
	AGTOB0, AGTOB1	Output	Output compare match B output					
RTC	RTCOUT	Output	Output pin for 1-Hz/64-Hz clock					
	RTCIC0 to RTCIC2	Input	Time capture event input pins					
SCI	SCK0 to SCK4, SCK9	I/O	Input/output pins for the clock (clock synchronous mode)					
	RXD0 to RXD4, RXD9	Input	Input pins for received data (asynchronous mode/clock synchronous mode					
	TXD0 to TXD4, TXD9	Output	Output pins for transmitted data (asynchronous mode/clock synchronous mode)					
	CTS0_RTS0 to CTS4_RTS4, CTS9_RTS9	I/O	Input/Output pins for controlling the start of transmission and reception (asynchronous mode/clock synchronous mode), active-low					
	SCL0 to SCL4, SCL9	I/O	Input/output pins for the IIC clock (simple IIC)					
	SDA0 to SDA4, SDA9	I/O	Input/output pins for the IIC data (simple IIC)					
	SCK0 to SCK4, SCK9	I/O	Input/output pins for the clock (simple SPI)					
	MISO0 to MISO4, MISO9	I/O	Input/output pins for slave transmission of data (simple SPI)					
	MOSI0 to MOSI4, MOSI9	I/O	Input/output pins for master transmission of data (simple SPI)					
	SS0 to SS4, SS9	Input	Slave-select input pins (simple SPI), active-low					
IIC	SCL0 to SCL2	I/O	Input/output pins for clock					
	SDA0 to SDA2	I/O	Input/output pins for data					
SSIE	SSIBCK0	I/O	SSIE serial bit clock pin					
	SSILRCK0/SSIFS0	I/O	Word select pins					
	SSITXD0	Output	Serial data output pins					
	SSIRXD0	Input	Serial data input pins					
	AUDIO_CLK	Input	External clock pin for audio (input oversampling clock)					
SPI	RSPCKA, RSPCKB	I/O	Clock input/output pin					
	MOSIA, MOSIB	I/O	Inputs or outputs data output from the master					
	MISOA, MISOB	I/O	Inputs or outputs data output from the slave					
	SSLA0, SSLB0	I/O	Input or output pin for slave selection					
	SSLA1, SSLA2, SSLA3, SSLB1, SSLB2, SSLB3	Output	Output pin for slave selection					



Function	Signal	I/O	Description
I/O ports	P000 to P015	I/O	General-purpose input/output pins
	P100 to P115	I/O	General-purpose input/output pins
	P200	Input	General-purpose input pin
	P201 to P206, P212, P213	I/O	General-purpose input/output pins
	P214, P215	Input	General-purpose input pins
	P300 to P315	I/O	General-purpose input/output pins
	P400 to P415	I/O	General-purpose input/output pins
	P500 to P507, P511, P512	I/O	General-purpose input/output pins
	P600 to P606, P608 to P614	I/O	General-purpose input/output pins
	P700 to P705, P708 to P713	I/O	General-purpose input/output pins
	P800 to P809	I/O	General-purpose input/output pins
	P900 to P902, P914, P915	I/O	General-purpose input/output pins
SLCDC	VL1, VL2, VL3, VL4	I/O	Voltage pin for driving the LCD
	CAPH, CAPL	I/O	Capacitor connection pin for the LCD controller/driver
	COM0 to COM7	Output	Common signal output pins for the LCD controller/driver
	SEG00 to SEG53	Output	Segment signal output pins for the LCD controller/driver

Pin nu	ımber						بد				Timer	s			Comn	nunicat	ion int	erfaces	s		Analo	gs		НМІ	
LGA145	LQFP144	BGA121	LQFP100	LGA100	LQFP64	QFN64	Power, System, Clock, Debug, CAC, VBATT	Interrupt	OII P411	External bus	AGT	GPT_OPS, POEG	GPT	RTC	USBFS,CAN	SCI	2	SPI/QSPI	SSIE	SDHI	ADC14	DAC12, OPAMP	ACMPLP	SLCDC	стѕи
D11	32	C11	21	D8	12	12						GTOV UP				TXD0/ MOSI0 /SDA0 CTS3_ RTS3/ SS3		MOSIA		SD0D AT0				SEG7	TS7
C12	33	C10	22	E6	13	13		IRQ5	P410		AGTO B1	GTOV LO	GTIOC 9B			SCK3 RXD0/ MISO0 /SCL0		MISOA		SD0D AT1				SEG8	TS6
B13	34	C9	23	B10	14	14		IRQ6	P409			GTOW UP	GTIOC 5A		USB_E XICEN	TXD3/ MOSI3								SEG9	TS5
D10	35	B11	24	D7	15	15		IRQ7	P408			GTOW LO	GTIOC 5B			CTS1_ RTS1/ SS1 RXD3/ MISO3 /SCL3	SCL0							SEG10	TS4
A13	36	A11	25	A10	16	16			P407		AGTIO 0			RTCO UT	USB_V BUS	CTS4_ RTS4/ SS4	SDA0	SSLB3			ADTR G0			SEG11	TS3
B11	37	B9	26	B8	17	17	VSS_U SB																		
A12	38	A10	27	A9	18	18			P915						USB_ DM										
B12	39 40	B10 A9	28	B9 A8	19	19	VCC_		P914						USB_ DP										
C11	41	B8	30	C8	21	21	USB																		
							VCC_ USB_L DO																		
B10	42	C8	31	C7	22	22		IRQ0	P206	WAIT		GTIU			USB_V BUSE N	RXD4/ MISO4 /SCL4	SDA1	SSLB1		SD0D AT2				SEG12	TS1
A10	43	A8	32	A7	23	23	CLKO UT	IRQ1	P205	A16	AGTO 1	GTIV	GTIOC 4A		USB_ OVRC URA	TXD4/ MOSI4 /SDA4 CTS9_ RTS9/ SS9	SCL1	SSLB0		SD0D AT3				SEG20	TSCA P
C10	44	D8	33	B7	24	24	CACR EF		P204	A18	AGTIO 1	GTIW	GTIOC 4B		USB_ OVRC URB	SCK4 SCK9	SCL0	RSPC KB		SD0D AT4				SEG23	TS0
A9	45	A7	34	D6				IRQ2	P203	A19			GTIOC 5A			CTS2_ RTS2/ SS2 TXD9/ MOSI9 /SDA9		MOSIB		SD0D AT5				SEG22	TSCA P
C9	46	В7	35	C6				IRQ3	P202	WR1/ BC1			GTIOC 5B			SCK2 RXD9/ MISO9 /SCL9		MISOB		SD0D AT6				SEG21	
B9	47	C7							P313	A20										SD0D AT7					
D9	48	D7								A21											ADTR G0				
D8	49	E7							P315	A22						RXD4/ MISO4 /SCL4									
A8	50								P900	A23						TXD4/ MOSI4									
B8	51					-			P901		AGTIO 1					/SDA4 SCK4									
B7	52								P902		AGTO 1					CTS4_ RTS4/									
A7	53	A6	36	A6		-	VSS									SS4									
A6	54	B6	37	B6			VCC																		
C7	55	C6	38	D5	25	25	RES																		
B6	56	D6	39	B5	26	26	MD		P201																
	<u> </u>	1	<u> </u>	1	<u> </u>	1	1	1	1	1	<u> </u>	<u> </u>	1	1	<u> </u>	<u> </u>					1				<u> </u>

#### 2.1 Absolute Maximum Ratings

Table 2.1 Absolute maximum ratings

Parameter		Symbol	Value	Unit	
Power supply voltage		VCC	-0.5 to +6.5	V	
Input voltage	5V-tolerant ports*1	V <sub>in</sub>	-0.3 to +6.5	V	
	P000 to P015	V <sub>in</sub>	-0.3 to AVCC0 + 0.3	V	
	Others	V <sub>in</sub>	-0.3 to VCC + 0.3	V	
Reference power supply	voltage	VREFH0	-0.3 to +6.5	V	
		VREFH		V	
VBATT power supply volt	age	VBATT	-0.5 to +6.5	V	
Analog power supply volt	age	AVCC0	-0.5 to +6.5	V	
USB power supply voltag	е	VCC_USB	-0.5 to +6.5	V	
		VCC_USB_LDO	-0.5 to +6.5	V	
Analog input voltage	When AN000 to AN015 are used	V <sub>AN</sub>	-0.3 to AVCC0 + 0.3	V	
	When AN016 to AN027 are used	1	-0.3 to VCC + 0.3	V	
LCD voltage	VL1 voltage	$V_{L1}$	-0.3 to +2.8	V	
	VL2 voltage	$V_{L2}$	-0.3 to +6.5	V	
	VL3 voltage	$V_{L3}$	-0.3 to +6.5	V	
	VL4 voltage	$V_{L4}$	-0.3 to +6.5	V	
Operating temperature*2,	*3,*4	T <sub>opr</sub>	-40 to +105	°C	
			-40 to +85		
Storage temperature		T <sub>stg</sub>	-55 to +125	°C	

Note 1. Ports P205, P206, P400 to P404, P407, P408, P511, P512 are 5V-tolerant.

#### Caution:

Permanent damage to the MCU may result if absolute maximum ratings are exceeded.

To preclude any malfunctions due to noise interference, insert capacitors of high frequency characteristics between the VCC and VSS pins, between the AVCC0 and AVSS0 pins, between the VCC\_USB and VSS\_USB pins, between the VREFH0 and VREFL0 pins, and between the VREFH and VREFL pins. Place capacitors of about 0.1  $\mu\text{F}$  as close as possible to every power supply pin and use the shortest and heaviest possible traces. Also, connect capacitors as stabilization capacitance.

Connect the VCL pin to a VSS pin by a 4.7 µF capacitor. The capacitor must be placed close to the pin. Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up might cause malfunction and the abnormal current that passes in the device at this time might cause degradation of internal elements.

Note 2. See section 2.2.1, Tj/Ta Definition.

Note 3. Contact Renesas Electronics sales office for information on derating operation under Ta = +85°C to +105°C. Derating is the systematic reduction of load for improved reliability.

Note 4. The upper limit of operating temperature is 85°C or 105°C, depending on the product. For details, see section 1.3, Part Numbering

# 2.2.5 I/O Pin Output Characteristics of Low Drive Capacity

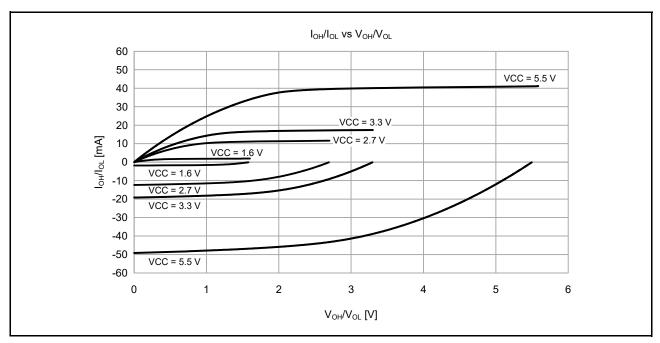


Figure 2.2  $V_{OH}/V_{OL}$  and  $I_{OH}/I_{OL}$  voltage characteristics at Ta = 25°C when low drive output is selected (reference data)

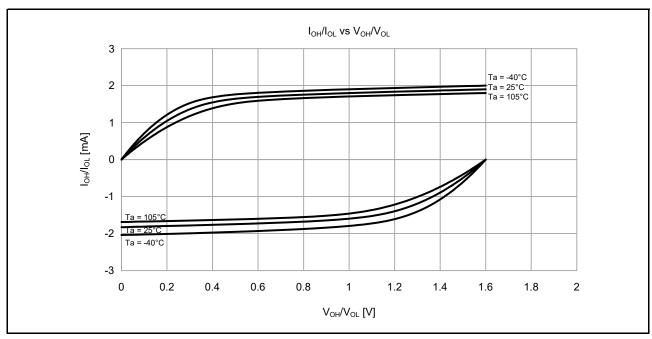


Figure 2.3  $V_{OH}/V_{OL}$  and  $I_{OH}/I_{OL}$  temperature characteristics at VCC = 1.6 V when low drive output is selected (reference data)

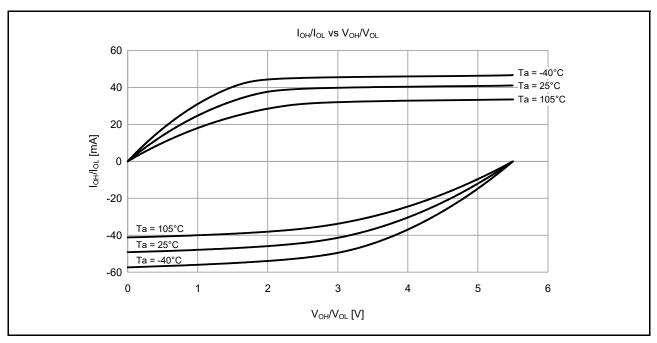


Figure 2.6  $V_{OH}/V_{OL}$  and  $I_{OH}/I_{OL}$  temperature characteristics at VCC = 5.5 V when low drive output is selected (reference data)

### 2.2.6 I/O Pin Output Characteristics of Middle Drive Capacity

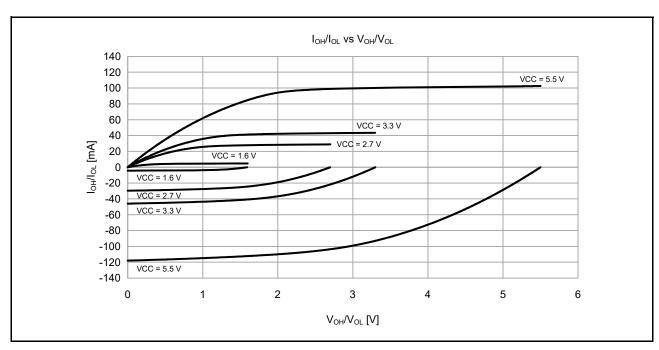


Figure 2.7  $V_{OH}/V_{OL}$  and  $I_{OH}/I_{OL}$  voltage characteristics at Ta = 25°C when middle drive output is selected (reference data)

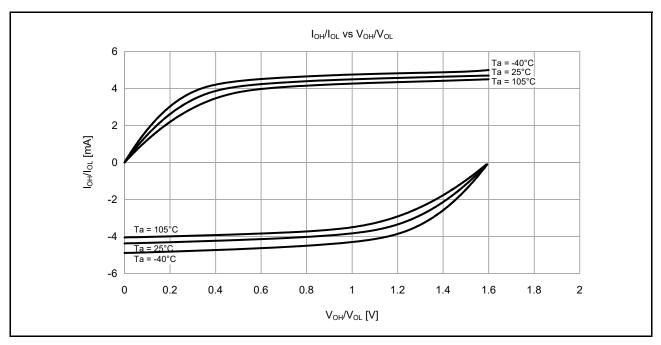


Figure 2.8  $V_{OH}/V_{OL}$  and  $I_{OH}/I_{OL}$  temperature characteristics at VCC = 1.6 V when middle drive output is selected (reference data)

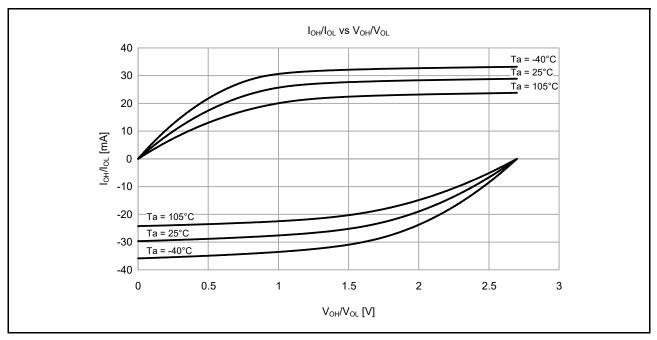


Figure 2.9  $V_{OH}/V_{OL}$  and  $I_{OH}/I_{OL}$  temperature characteristics at VCC = 2.7 V when middle drive output is selected (reference data)

S3A3 Datasheet 2. Electrical Characteristics

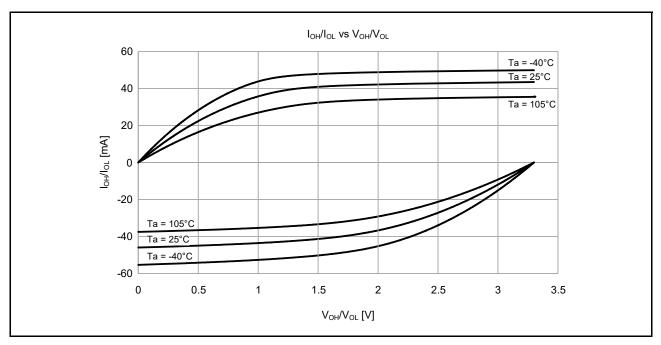


Figure 2.10  $V_{OH}/V_{OL}$  and  $I_{OH}/I_{OL}$  temperature characteristics at VCC = 3.3 V when middle drive output is selected (reference data)

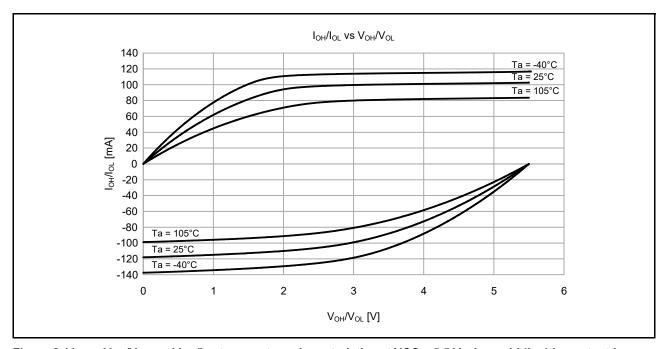


Figure 2.11  $V_{OH}/V_{OL}$  and  $I_{OH}/I_{OL}$  temperature characteristics at VCC = 5.5 V when middle drive output is selected (reference data)

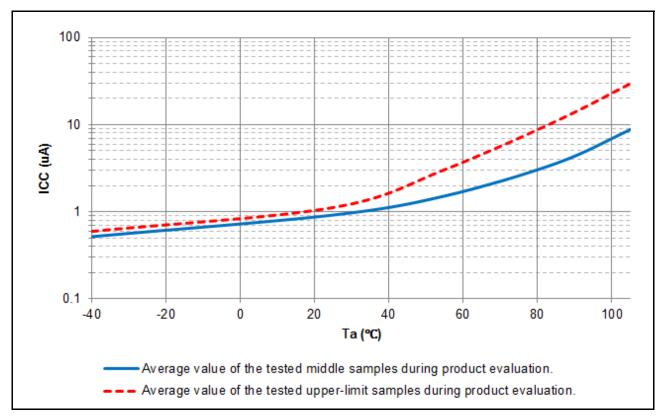


Figure 2.22 Temperature dependency in Software Standby mode 48-KB SRAM on (reference data)

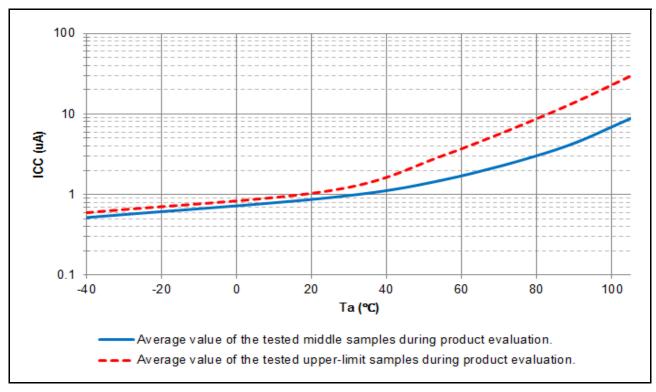


Figure 2.23 Temperature dependency in Software Standby mode all SRAM on (reference data)

Table 2.14 Operating and standby current (4)

Conditions: VCC = AVCC0 = 1.6 to 5.5 V, VREFH0 = 2.7 V to AVCC0

Parameter			Symbol	Min	Тур	Max	Unit	Test conditions
Analog power	During A/D conversion (at	high-speed conversion)	I <sub>AVCC</sub>	-	-	3.0	mA	-
supply current	During A/D conversion (at	low power conversion)		-	-	1.0	mA	-
	During D/A conversion (pe	r channel)*1		-	0.4	0.8	mA	-
	Waiting for A/D and D/A co	onversion (all units)*6		-	-	1.0	μA	-
Reference	During A/D conversion		I <sub>REFH0</sub>	-	-	150	μA	-
power supply current	Waiting for A/D conversion	(all units)		-	-	60	nA	-
	During D/A conversion		I <sub>REFH</sub>	-	50	100	μΑ	-
	Waiting for D/A conversion	(all units)		-	-	100	μΑ	-
Temperature sensor			I <sub>TNS</sub>	-	75	-	μΑ	-
Low-Power	Window mode		I <sub>CMPLP</sub>	-	15	-	μΑ	-
Analog Comparator	Comparator High-speed m	ode		-	10	-	μΑ	-
operating current	Comparator Low-speed m	ode		-	2	-	μA	-
J. 10110	Comparator Low-speed m	ode using DAC8		-	820	-	μΑ	-
Operational	Low power mode	1 unit operating	I <sub>AMP</sub>	-	2.5	4.0	μΑ	-
Amplifier operating		2 units operating		-	4.5	8.0	μΑ	-
current		3 units operating		-	6.5	11.0	μΑ	-
		4 units operating		-	8.5	14.0	μΑ	-
	High speed mode	1 unit operating		-	140	220	μΑ	-
		2 units operating		-	280	410	μΑ	-
		3 units operating		-	420	600	μΑ	-
		4 units operating		-	560	780	μA	-
LCD operating current	External resistance divisio f <sub>LCD</sub> = f <sub>SUB</sub> = 128 Hz, 1/3		I <sub>LCD1</sub> *5	-	0.34	-	μА	-
	Internal voltage boosting n f <sub>LCD</sub> = f <sub>SUB</sub> = 128 Hz, 1/3	nethod (VLCD.VLCD = 04) bias, and 4-time slice	I <sub>LCD2</sub> *5	-	0.92	-	μА	-
	Capacitor split method f <sub>LCD</sub> = f <sub>SUB</sub> = 128 Hz, 1/3	bias, and 4-time slice	I <sub>LCD3</sub> *5	-	0.19	-	μA	-
USB operating current	During USB communication following settings and concept Host controller operation Bulk OUT transfer (64 bulk IN transfer (64 byte)  Connect peripheral devicable from the USB port	ditions:  n is set to full-speed mode ytes) × 1, s) × 1 ces via a 1-meter USB	I <sub>USBH</sub> *2	-	4.3 (VCC) 0.9 (VCC_USB)*4	-	mA	-
	During USB communication following settings and conception of the Device controller operated Bulk OUT transfer (64 bulk IN transfer (64 byte)  Connect the host device from the USB port.	ditions: ion is set to full-speed mode ytes) × 1, s) × 1	I <sub>USBF</sub> *2	-	3.6 (VCC) 1.1 (VCC_USB)*4	-	mA	-
	During suspended state un and conditions:  Device controller operat (pull up the USB_DP pir Software standby mode  Connect the host device from the USB port.	ion is set to full-speed mode	I <sub>SUSP</sub> *3	-	0.35 (VCC) 170 (VCC_USB)*4	-	μΑ	-

- Note 1. The reference power supply current is included in the power supply current value for D/A conversion.
- Note 2. Current consumed only by the USBFS.
- Note 3. Includes the current supplied from the pull-up resistor of the USB\_DP pin to the pull-down resistor of the host device, in addition to the current consumed by the MCU during the suspended state.
- Note 4. When VCC = VCC\_USB = 3.3 V.
- Note 5. Current flowing only to the LCD controller. Not including the current that flows through the LCD panel.
- Note 6. When the MCU is in Software Standby mode or the MSTPCRD.MSTPD16 (ADC140 Module Stop bit) is in the module-stop state.



- Note 3. See section 9, Clock Generation Circuit in User's Manual for the relationship of frequencies between ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK.
- Note 4. The maximum value of operation frequency does not include the internal oscillator errors. The operation can be guaranteed with the errors of the internal oscillator. For details on the range for guaranteed operation, see Table 2.22, Clock timing.

Table 2.20 Operation frequency value in low-voltage mode

Conditions: VCC = AVCC0 = 1.6 to 5.5 V

Parameter			Symbol	Min	Тур	Max*5	Unit
Operation	System clock (ICLK)*4	1.6 to 5.5 V	f	0.032768	-	4	MHz
frequency	FlashIF clock (FCLK)*1, *2, *4	1.6 to 5.5 V	1	0.032768	-	4	
	Peripheral module clock (PCLKA)*4	1.6 to 5.5 V	1	-	-	4	
	Peripheral module clock (PCLKB)*4	1.6 to 5.5 V	1	-	-	4	
	Peripheral module clock (PCLKC)*3, *4	1.6 to 5.5 V	1	-	-	4	
	Peripheral module clock (PCLKD)*4	1.6 to 5.5 V	1	-	-	4	
	External bus clock (BCLK)*4	1.6 to 5.5 V		-	-	4	
	EBCLK pin output	1.8 to 5.5 V	1	-	-	4	
		1.6 to 1.8 V	1	-	-	2	

- Note 1. The lower-limit frequency of FCLK is 1 MHz while programming or erasing the flash memory. When using FCLK for programming or erasing the flash memory at below 4 MHz, the frequency can be set to 1 MHz, 2 MHz, or 3 MHz. A non-integer frequency such as 1.5 MHz cannot be set.
- Note 2. The frequency accuracy of FCLK must be ±3.5% while programming or erasing the flash memory. Confirm the frequency accuracy of the clock source.
- Note 3. The lower-limit frequency of PCLKC is 4 MHz at 2.4 V or above and 1 MHz at below 2.4 V when the 14-bit A/D converter is in use.
- Note 4. See section 9, Clock Generation Circuit in User's Manual for the relationship of frequencies between ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK.
- Note 5. The maximum value of operation frequency does not include errors of the internal oscillator. The operation can be guaranteed with the errors of the internal oscillator. For details on the range for guaranteed operation, see Table 2.22, Clock timing.

Table 2.21 Operation frequency value in Subosc-speed mode

Conditions: VCC = AVCC0 = 1.8 to 5.5 V

Parameter			Symbol	Min	Тур	Max	Unit
Operation	System clock (ICLK)*3	1.8 to 5.5 V	f	27.8528	32.768	37.6832	kHz
frequency	FlashIF clock (FCLK)*1, *3	1.8 to 5.5 V		27.8528	32.768	37.6832	
	Peripheral module clock (PCLKA)*3	1.8 to 5.5 V		-	-	37.6832	
	Peripheral module clock (PCLKB)*3	1.8 to 5.5 V		-	-	37.6832	
	Peripheral module clock (PCLKC)*2, *3	1.8 to 5.5 V	1	-	-	37.6832	
	Peripheral module clock (PCLKD)*3	1.8 to 5.5 V		-	-	37.6832	
	External bus clock (BCLK)*3	1.8 to 5.5 V		-	-	37.6832	
	EBCLK pin output	1.8 to 5.5 V		-	-	37.6832	

- Note 1. Programming and erasing the flash memory is not possible.
- Note 2. The 14-bit A/D converter cannot be used.
- Note 3. See section 9, Clock Generation Circuit in User's Manual for the relationship of frequencies between ICLK, PCLKA, PCLKB, PCLKC, PCLKD, FCLK, and BCLK.

#### Table 2.33 Bus timing (3)

Conditions: Low drive output is selected in the Port Drive Capability in PmnPFS register

VCC = 1.8 to 2.4 V

Output load conditions:  $V_{OH}$  = VCC × 0.5,  $V_{OL}$  = VCC × 0.5, C = 30 pF

Parameter	Symbol	Min	Max	Unit	Test conditions
Address delay	t <sub>AD</sub>	-	90	ns	Figure 2.42
Byte control delay	t <sub>BCD</sub>	-	90	ns	to Figure 2.45
CS delay	t <sub>CSD</sub>	-	90	ns	
ALE delay time	t <sub>ALED</sub>	-	90	ns	
RD delay	t <sub>RSD</sub>	-	90	ns	
Read data setup time	t <sub>RDS</sub>	70	-	ns	
Read data hold time	t <sub>RDH</sub>	0	-	ns	
WR delay	t <sub>WRD</sub>	-	90	ns	
Write data delay	t <sub>WDD</sub>	-	90	ns	
Write data hold time	t <sub>WDH</sub>	0	-	ns	
WAIT setup time	t <sub>WTS</sub>	70	-	ns	Figure 2.46
WAIT hold time	t <sub>WTH</sub>	0	-	ns	

#### Table 2.34 Bus timing (4)

Conditions: Low drive output is selected in the Port Drive Capability in PmnPFS register

VCC = 1.6 to 1.8 V

Output load conditions:  $V_{OH}$  = VCC × 0.5,  $V_{OL}$  = VCC × 0.5, C = 30 pF

Parameter	Symbol	Min	Max	Unit	Test conditions
Address delay	t <sub>AD</sub>	-	120	ns	Figure 2.42
Byte control delay	t <sub>BCD</sub>	-	120	ns	to Figure 2.45
CS delay	t <sub>CSD</sub>	-	120	ns	
ALE delay time	t <sub>ALED</sub>	-	120	ns	
RD delay	t <sub>RSD</sub>	-	120	ns	
Read data setup time	t <sub>RDS</sub>	90	-	ns	
Read data hold time	t <sub>RDH</sub>	0	-	ns	
WR delay	t <sub>WRD</sub>	-	120	ns	
Write data delay	t <sub>WDD</sub>	-	120	ns	
Write data hold time	t <sub>WDH</sub>	0	-	ns	
WAIT setup time	t <sub>WTS</sub>	90	-	ns	Figure 2.46
WAIT hold time	t <sub>WTH</sub>	0	-	ns	

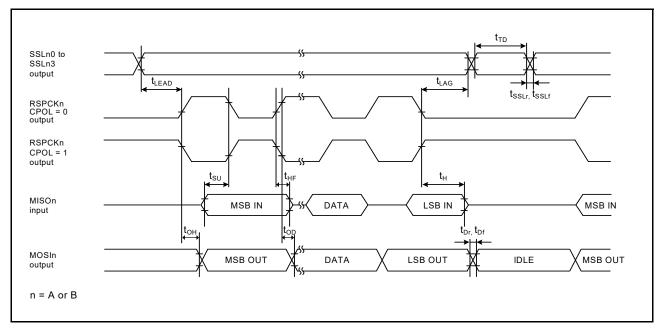


Figure 2.65 SPI timing (master, CPHA = 1) (bit rate: PCLKA division ratio is set to 1/2)

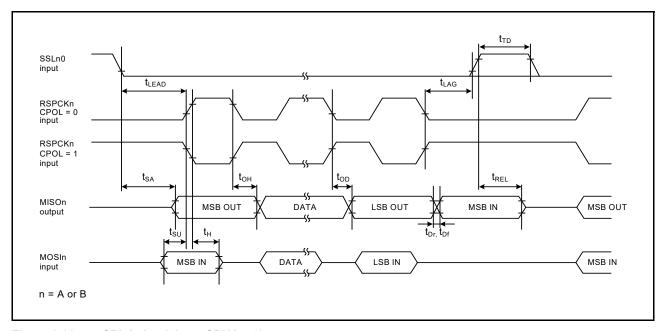


Figure 2.66 SPI timing (slave, CPHA = 0)

### 2.3.15 CLKOUT Timing

Table 2.45 CLKOUT timing

Parameter			Symbol	Min	Max	Unit*1	Test conditions
CLKOUT	CLKOUT pin output cycle*1	VCC = 2.7 V or above	t <sub>Ccyc</sub>	62.5	-	ns	Figure 2.76
		VCC = 1.8 V or above		125	-		
		VCC = 1.6 V or above		250	-		
	CLKOUT pin high pulse width*2	VCC = 2.7 V or above	t <sub>CH</sub>	15	-	ns	
		VCC = 1.8 V or above		30	-		
		VCC = 1.6 V or above	1	150	-		
	CLKOUT pin low pulse width*2	VCC = 2.7 V or above	t <sub>CL</sub>	15	-	ns	
		VCC = 1.8 V or above	1	30	-		
		VCC = 1.6 V or above	1	150	-		
	CLKOUT pin output rise time	VCC = 2.7 V or above	t <sub>Cr</sub>	-	12	ns	
		VCC = 1.8 V or above	1	-	25		
		VCC = 1.6 V or above	1	-	50		
	CLKOUT pin output fall time	VCC = 2.7 V or above	t <sub>Cf</sub>	-	12	ns	
		VCC = 1.8 V or above	1	-	25		
		VCC = 1.6 V or above	1	-	50		

- Note 1. When the EXTAL external clock input or an oscillator is used with division by 1 (the CKOCR.CKOSEL[2:0] bits are 011b and the CKOCR.CKODIV[2:0] bits are 000b) to output from CLKOUT, the above should be satisfied with an input duty cycle of 45 to 55%.
- Note 2. When the MOCO is selected as the clock output source (the CKOCR.CKOSEL[2:0] bits are 001b), set the clock output division ratio selection to be divided by 2 (the CKOCR.CKODIV[2:0] bits are 001b).

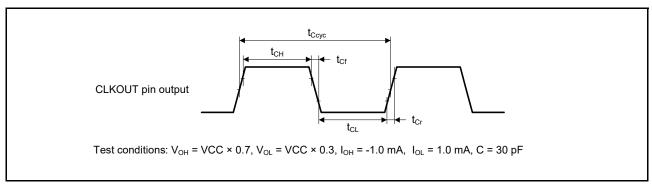


Figure 2.76 CLKOUT output timing

<b>Table 2.63</b>	Power-on reset	circuit and voltage	detection circ	uit characteristics (2)	١

Parameter		Symbol	Min	Тур	Max	Unit	Test conditions
Wait time after power-on reset cancellation	LVD0:enable	t <sub>POR</sub>	-	1.7	-	ms	-
reset our conduction	LVD0:disable	t <sub>POR</sub>	-	1.3	-	ms	-
Wait time after voltage monitor 0,1,2 reset	LVD0:enable*1	t <sub>LVD0,1,2</sub>	-	0.6	-	ms	-
cancellation	LVD0:disable*2	t <sub>LVD1,2</sub>	-	0.2	-	ms	-
Response delay*3	1	t <sub>det</sub>	-	-	350	μs	Figure 2.85, Figure 2.86
Minimum VCC down time		t <sub>VOFF</sub>	450	-	-	μs	Figure 2.85, VCC = 1.0 V or above
Power-on reset enable time		t <sub>W (POR)</sub>	1	-	-	ms	Figure 2.86, VCC = below 1.0 V
LVD operation stabilization time (after LVD is enabled)		t <sub>d (E-A)</sub>	-	-	300	μs	Figure 2.88, Figure 2.89
Hysteresis width (POR)		V <sub>PORH</sub>	-	110	-	mV	-
Hysteresis width (LVD0, LV	/D1, and LVD2)	$V_{LVH}$	-	60	-	mV	LVD0 selected
			-	100	-		V <sub>det1_0</sub> to V <sub>det1_2</sub> selected
			-	60	-		V <sub>det1_3</sub> to V <sub>det1_9</sub> selected
			-	50	-		V <sub>det1_A</sub> or V <sub>det1_B</sub> selected
			-	40	-		V <sub>det1_C</sub> or V <sub>det1_F</sub> selected
			-	60	-		LVD2 selected

- Note 1. When OFS1.LVDAS = 0.
- Note 2. When OFS1.LVDAS = 1.
- Note 3. The minimum VCC down time indicates the time when VCC is below the minimum value of voltage detection levels  $V_{POR}$ , Vdet0, Vdet1, and Vdet2 for the POR/LVD.

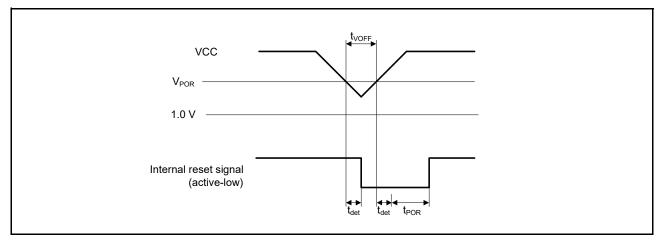


Figure 2.85 Voltage detection reset timing

### 2.15 Flash Memory Characteristics

### 2.15.1 Code Flash Memory Characteristics

Table 2.75 Code flash characteristics (1)

Parameter		Symbol	Min	Тур	Max	Unit	Test conditions
Reprogramming/erasure cycle*1		N <sub>PEC</sub>	1000	-	-	Times	-
Data hold time	After 1000 times of N <sub>PEC</sub>	t <sub>DRP</sub>	20*2, *3	-	-	Year	T <sub>a</sub> = +85°C

- Note 1. The reprogram/erase cycle is the number of erasures for each block. When the reprogram/erase cycle is n times (n = 1,000), erasing can be done n times for each block. For instance, when 8-byte programming is performed 256 times for different addresses in 2-KB blocks, and then the entire block is erased, the reprogram/erase cycle is counted as one. However, programming the same address for several times as one erasure is not enabled (overwriting is prohibited).
- Note 2. Characteristic when using the flash memory programmer and the self-programming library provided by Renesas Electronics.
- Note 3. This result is obtained from reliability testing.

Table 2.76 Code flash characteristics (2)

High-speed operating mode Conditions: VCC = 2.7 to 5.5 V

Parameter				FCLK = 1 N	ЛHz		FCLK = 32	MHz	
		Symbol	Min	Тур	Max	Min	Тур	Max	Unit
Programming time	8-byte	t <sub>P8</sub>	-	116	998	-	54	506	μs
Erasure time	2-KB	t <sub>E2K</sub>	-	9.03	287	-	5.67	222	ms
Blank check time	8-byte	t <sub>BC8</sub>	-	-	56.8	-	-	16.6	μs
	2-KB	t <sub>BC2K</sub>	-	-	1899	-	-	140	μs
Erase suspended tim	е	t <sub>SED</sub>	-	-	22.5	-	-	10.7	μs
Startup area switchin	g setting time	t <sub>SAS</sub>	-	21.7	585	-	12.1	447	ms
Access window time		t <sub>AWS</sub>	-	21.7	585	-	12.1	447	ms
OCD/serial programn	ner ID setting time	t <sub>OSIS</sub>	-	21.7	585	-	12.1	447	ms
Flash memory mode time 1	transition wait	t <sub>DIS</sub>	2	-	-	2	-	-	μs
Flash memory mode time 2	transition wait	t <sub>MS</sub>	5	-	-	5	-	-	μs

Note: Does not include the time until each operation of the flash memory is started after instructions are executed by software.

Note: The lower-limit frequency of FCLK is 1 MHz during programming or erasing the flash memory. When using FCLK at below

4 MHz, the frequency can be set to 1 MHz, 2 MHz, or 3 MHz. A non-integer frequency such as 1.5 MHz cannot be set.

Note: The frequency accuracy of FCLK must be ±3.5%. Confirm the frequency accuracy of the clock source.

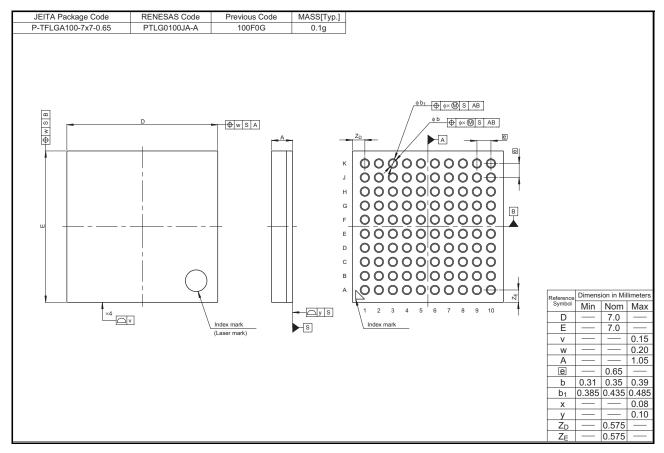


Figure 1.4 LGA 100-pin